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20.2.1 TXD — Transmit Pin	726
20.2.2 RXD — Receive Pin	726
20.3 Memory Map and Register Definition	726
20.3.1 Module Memory Map and Register Definition	726
20.3.2 Register Descriptions	727
20.4 Functional Description	739
20.4.1 Infrared Interface Submodule	740
20.4.2 LIN Support	740
20.4.3 Data Format	741
20.4.4 Baud Rate Generation	742
20.4.5 Transmitter	743
20.4.6 Receiver	748
20.4.7 Single-Wire Operation	756
20.4.8 Loop Operation	757
20.5 Initialization/Application Information	757
20.5.1 Reset Initialization	757
20.5.2 Modes of Operation	757
20.5.3 Interrupt Operation	758
20.5.4 Recovery from Wait Mode	760
20.5.5 Recovery from Stop Mode	760

Chapter 21 Serial Peripheral Interface (S12SPIV5)

21.1	Introduction	
	21.1.1 Glossary of Terms	
	21.1.2 Features	
	21.1.3 Modes of Operation	
	21.1.4 Block Diagram	
21.2	External Signal Description	
	21.2.1 MOSI — Master Out/Slave In Pin	
	21.2.2 MISO — Master In/Slave Out Pin	
	21.2.3 $\overline{\text{SS} - \text{Slave Select Pin}}$	
	21.2.4 SCK — Serial Clock Pin	
21.3	Memory Map and Register Definition	
	21.3.1 Module Memory Map	
	21.3.2 Register Descriptions	
21.4	Functional Description	
	21.4.1 Master Mode	
	21.4.2 Slave Mode	
	21.4.3 Transmission Formats	
	21.4.4 SPI Baud Rate Generation	
	21.4.5 Special Features	
	21.4.6 Error Conditions	
	21.4.7 Low Power Mode Options	



1.2.2 Pin Assignment Overview

Table 1-7 provides a summary of which Ports are available for each package option.

Routing of pin functions is summarized in Table 1-8.

Table 1-9 provides a pin out summary listing the availability of individual pins for each package option.



1.2.3.35 PJ5 / KWJ5 / SCL1 / CS2 — PORT J I/O Pin 5

PJ5 is a general-purpose input or output pin. It can be configured as a keypad wakeup input. It can be configured as the serial clock pin SCL of the IIC1 module. It can be also configured as chip-select output 2.

1.2.3.36 PJ4 / KWJ4 / SDA1 / CS0 — PORT J I/O Pin 4

PJ4 is a general-purpose input or output pin. It can be configured as a keypad wakeup input. It can be configured as the serial data pin SDA of the IIC1 module. It can also be configured as chip-select output.

1.2.3.37 PJ3 / KWJ3 — PORT J I/O Pin 3

PJ3 is a general-purpose input or output pins. It can be configured as a keypad wakeup input.

1.2.3.38 PJ2 / KWJ2 / CS1 — PORT J I/O Pin 2

PJ2 is a general-purpose input or output pins. It can be configured as a keypad wakeup input. It can also be configured as chip-select output.

1.2.3.39 PJ1 / KWJ1 / TXD2 — PORT J I/O Pin 1

PJ1 is a general-purpose input or output pin. It can be configured as a keypad wakeup input. It can be configured as the transmit pin TXD of the serial communication interface 2 (SCI2).

1.2.3.40 PJ0 / KWJ0 / RXD2 / CS3 — PORT J I/O Pin 0

PJ0 is a general-purpose input or output pin. It can be configured as a keypad wakeup input. It can be configured as the receive pin RXD of the serial communication interface 2 (SCI2). It can also be configured as chip-select output 3.

1.2.3.41 PK7 / EWAIT / ROMCTL — Port K I/O Pin 7

PK7 is a general-purpose input or output pin. During MCU emulation modes and normal expanded modes of operation, this pin is used to enable the Flash EEPROM memory in the memory map (ROMCTL). At the rising edge of $\overline{\text{RESET}}$, the state of this pin is latched to the ROMON bit. The $\overline{\text{EWAIT}}$ input signal maintains the external bus access until the external device is ready to capture data (write) or provide data (read).

The input voltage threshold for PK7 can be configured to reduced levels, to allow data from an external 3.3-V peripheral to be read by the MCU operating at 5.0 V.

1.2.3.42 PK[6:4] / ADDR[22:20] / ACC[2:0] — Port K I/O Pin [6:4]

PK[6:4] are general-purpose input or output pins. During MCU expanded modes of operation, the ACC[2:0] signals are used to indicate the access source of the bus cycle. These pins also provide the expanded addresses ADDR[22:20] for the external bus. In Emulation modes ACC[2:0] is available and is time multiplexed with the high addresses



compared to the serial communication rate. This protocol allows a great flexibility for the POD designers, since it does not rely on any accurate time measurement or short response time to any event in the serial communication.



Figure 7-11. Target Acknowledge Pulse (ACK)

NOTE

If the ACK pulse was issued by the target, the host assumes the previous command was executed. If the CPU enters wait or stop prior to executing a hardware command, the ACK pulse will not be issued meaning that the BDM command was not executed. After entering wait or stop mode, the BDM command is no longer pending.

Figure 7-12 shows the ACK handshake protocol in a command level timing diagram. The READ_BYTE instruction is used as an example. First, the 8-bit instruction opcode is sent by the host, followed by the address of the memory location to be read. The target BDM decodes the instruction. A bus cycle is grabbed (free or stolen) by the BDM and it executes the READ_BYTE operation. Having retrieved the data, the BDM issues an ACK pulse to the host controller, indicating that the addressed byte is ready to be retrieved. After detecting the ACK pulse, the host initiates the byte retrieval process. Note that data is sent in the form of a word and the host needs to determine which is the appropriate byte based on whether the address was odd or even.





8.4.5.1 Trace Trigger Alignment

Using the TALIGN bits (see Section 8.3.2.3) it is possible to align the trigger with the end, the middle, or the beginning of a tracing session.

If End or Mid tracing is selected, tracing begins when the ARM bit in DBGC1 is set and State1 is entered. The transition to Final State if End is selected signals the end of the tracing session. The transition to Final State if Mid is selected signals that another 32 lines will be traced before ending the tracing session. Tracing with Begin-Trigger starts at the opcode of the trigger.

8.4.5.1.1 Storing with Begin-Trigger

Storing with Begin-Trigger, data is not stored in the Trace Buffer until the Final State is entered. Once the trigger condition is met the S12XDBG module will remain armed until 64 lines are stored in the Trace Buffer. If the trigger is at the address of the change-of-flow instruction the change of flow associated with the trigger will be stored in the Trace Buffer. Using Begin-trigger together with tagging, if the tagged instruction is about to be executed then the trace is started. Upon completion of the tracing session the breakpoint is generated, thus the breakpoint does not occur at the tagged instruction boundary.

8.4.5.1.2 Storing with Mid-Trigger

Storing with Mid-Trigger, data is stored in the Trace Buffer as soon as the S12XDBG module is armed. When the trigger condition is met, another 32 lines will be traced before ending the tracing session, irrespective of the number of lines stored before the trigger occurred, then the S12XDBG module is disarmed and no more data is stored. Using Mid-trigger with tagging, if the tagged instruction is about to be executed then the trace is continued for another 32 lines. Upon tracing completion the breakpoint is generated, thus the breakpoint does not occur at the tagged instruction boundary.

8.4.5.1.3 Storing with End-Trigger

Storing with End-Trigger, data is stored in the Trace Buffer until the Final State is entered, at which point the S12XDBG module will become disarmed and no more data will be stored. If the trigger is at the address of a change of flow instruction the trigger event will not be stored in the Trace Buffer.

8.4.5.2 Trace Modes

The S12XDBG module can operate in four trace modes. The mode is selected using the TRCMOD bits in the DBGTCR register. In each mode tracing of XGATE or CPU12X information is possible. The source for the trace is selected using the TSOURCE bits in the DBGTCR register. The modes are described in the following subsections. The trace buffer organization is shown in Table 8-43.

8.4.5.2.1 Normal Mode

In Normal Mode, change of flow (COF) program counter (PC) addresses will be stored.

COF addresses are defined as follows for the CPU12X:

- Source address of taken conditional branches (long, short, bit-conditional, and loop primitives)
- Destination address of indexed JMP, JSR, and CALL instruction



	RTR[6:4] =											
RTR[3:0]	000 (OFF)	001 (2 ¹⁰)	010 (2 ¹¹)	011 (2 ¹²)	100 (2 ¹³)	101 (2 ¹⁴)	110 (2 ¹⁵)	111 (2 ¹⁶)				
0001 (÷2)	OFF	2x2 ¹⁰	2x2 ¹¹	2x2 ¹²	2x2 ¹³	2x2 ¹⁴	2x2 ¹⁵	2x2 ¹⁶				
0010 (÷3)	OFF	3x2 ¹⁰	3x2 ¹¹	3x2 ¹²	3x2 ¹³	3x2 ¹⁴	3x2 ¹⁵	3x2 ¹⁶				
0011 (÷4)	OFF	4x2 ¹⁰	4x2 ¹¹	4x2 ¹²	4x2 ¹³	4x2 ¹⁴	4x2 ¹⁵	4x2 ¹⁶				
0100 (÷5)	OFF	5x2 ¹⁰	5x2 ¹¹	5x2 ¹²	5x2 ¹³	5x2 ¹⁴	5x2 ¹⁵	5x2 ¹⁶				
0101 (÷6)	OFF	6x2 ¹⁰	6x2 ¹¹	6x2 ¹²	6x2 ¹³	6x2 ¹⁴	6x2 ¹⁵	6x2 ¹⁶				
0110 (÷7)	OFF	7x2 ¹⁰	7x2 ¹¹	7x2 ¹²	7x2 ¹³	7x2 ¹⁴	7x2 ¹⁵	7x2 ¹⁶				
0111 (÷8)	OFF	8x2 ¹⁰	8x2 ¹¹	8x2 ¹²	8x2 ¹³	8x2 ¹⁴	8x2 ¹⁵	8x2 ¹⁶				
1000 (÷9)	OFF	9x2 ¹⁰	9x2 ¹¹	9x2 ¹²	9x2 ¹³	9x2 ¹⁴	9x2 ¹⁵	9x2 ¹⁶				
1001 (÷10)	OFF	10x2 ¹⁰	10x2 ¹¹	10x2 ¹²	10x2 ¹³	10x2 ¹⁴	10x2 ¹⁵	10x2 ¹⁶				
1010 (÷11)	OFF	11x2 ¹⁰	11x2 ¹¹	11x2 ¹²	11x2 ¹³	11x2 ¹⁴	11x2 ¹⁵	11x2 ¹⁶				
1011 (÷12)	OFF	12x2 ¹⁰	12x2 ¹¹	12x2 ¹²	12x2 ¹³	12x2 ¹⁴	12x2 ¹⁵	12x2 ¹⁶				
1100 (÷13)	OFF	13x2 ¹⁰	13x2 ¹¹	13x2 ¹²	13x2 ¹³	13x2 ¹⁴	13x2 ¹⁵	13x2 ¹⁶				
1101 (÷14)	OFF	14x2 ¹⁰	14x2 ¹¹	14x2 ¹²	14x2 ¹³	14x2 ¹⁴	14x2 ¹⁵	14x2 ¹⁶				
1110 (÷15)	OFF	15x2 ¹⁰	15x2 ¹¹	15x2 ¹²	15x2 ¹³	15x2 ¹⁴	15x2 ¹⁵	15x2 ¹⁶				
1111 (÷16)	OFF	16x2 ¹⁰	16x2 ¹¹	16x2 ¹²	16x2 ¹³	16x2 ¹⁴	16x2 ¹⁵	16x2 ¹⁶				

Table 11-10. RTI Frequency Divide Rates for RTDEC = 0

1. Denotes the default value out of reset. This value should be used to disable the RTI to ensure future backwards compatibility.

Table 11-11. RTI Frequency Divide Rates for RTDEC=1

	RTR[6:4] =										
RTR[3:0]	000 (1x10 ³)	001 (2x10 ³)	010 (5x10 ³)	011 (10x10 ³)	100 (20x10 ³)	101 (50x10 ³)	110 (100x10 ³)	111 (200x10 ³)			
0000 (÷1)	1x10 ³	2x10 ³	5x10 ³	10x10 ³	20x10 ³	50x10 ³	100x10 ³	200x10 ³			
0001 (÷2)	2x10 ³	4x10 ³	10x10 ³	20x10 ³	40x10 ³	100x10 ³	200x10 ³	400x10 ³			
0010 (÷3)	3x10 ³	6x10 ³	15x10 ³	30x10 ³	60x10 ³	150x10 ³	300x10 ³	600x10 ³			
0011 (÷4)	4x10 ³	8x10 ³	20x10 ³	40x10 ³	80x10 ³	200x10 ³	400x10 ³	800x10 ³			
0100 (÷5)	5x10 ³	10x10 ³	25x10 ³	50x10 ³	100x10 ³	250x10 ³	500x10 ³	1x10 ⁶			
0101 (÷6)	6x10 ³	12x10 ³	30x10 ³	60x10 ³	120x10 ³	300x10 ³	600x10 ³	1.2x10 ⁶			



Register Name	Bit 7	6	5	4	3	2	1	Bit 0
0x003A R	TC15	TC14	TC13	TC12	TC11	TC10	TC9	TC8
TC1H (High) W								
0x003B R	TC7	TC6	TC5	TC4	TC3	TC2	TC1	TC0
TC1H (Low) W								
0x003C R	TC15	TC14	TC13	TC12	TC11	TC10	TC9	TC8
TC2H (High) W								
0x003D R	TC7	TC6	TC5	TC4	TC3	TC2	TC1	TC0
TC2H (Low) W								
0x003E R	TC15	TC14	TC13	TC12	TC11	TC10	TC9	TC8
TC3H (High) W								
0x003F R	TC7	TC6	TC5	TC4	TC3	TC2	TC1	TC0
TC3H (Low) W								
		= Unimpleme	ented or Rese	rved				

Figure 14-2. ECT Register Summary (Sheet 5 of 5)

14.3.2.1 Timer Input Capture/Output Compare Select Register (TIOS)

Module Base + 0x0000



Figure 14-3. Timer Input Capture/Output Compare Register (TIOS)

Read or write: Anytime

All bits reset to zero.

Table 14-2. TIOS Field Descriptions

Field	Description
7:0	Input Capture or Output Compare Channel Configuration
IOS[7:0]	0 The corresponding channel acts as an input capture.1 The corresponding channel acts as an output compare.



16.2 External Signal Description

The MSCAN uses two external pins.

NOTE

On MCUs with an integrated CAN physical interface (transceiver) the MSCAN interface is connected internally to the transceiver interface. In these cases the external availability of signals TXCAN and RXCAN is optional.

16.2.1 RXCAN — CAN Receiver Input Pin

RXCAN is the MSCAN receiver input pin.

16.2.2 TXCAN — CAN Transmitter Output Pin

TXCAN is the MSCAN transmitter output pin. The TXCAN output pin represents the logic level on the CAN bus:

0 = Dominant state

1 =Recessive state

16.2.3 CAN System

A typical CAN system with MSCAN is shown in Figure 16-2. Each CAN station is connected physically to the CAN bus lines through a transceiver device. The transceiver is capable of driving the large current needed for the CAN bus and has current protection against defective CAN or defective stations.



Figure 16-2. CAN System



20.3.2.3 SCI Alternative Status Register 1 (SCIASR1)

Module Base + 0x0000



Read: Anytime, if AMAP = 1

Write: Anytime, if AMAP = 1

Table 20-6. SCIASR1 Field Descriptions

Field	Description
7 RXEDGIF	Receive Input Active Edge Interrupt Flag — RXEDGIF is asserted, if an active edge (falling if RXPOL = 0, rising if RXPOL = 1) on the RXD input occurs. RXEDGIF bit is cleared by writing a "1" to it. 0 No active receive on the receive input has occurred 1 An active edge on the receive input has occurred
2 BERRV	 Bit Error Value — BERRV reflects the state of the RXD input when the bit error detect circuitry is enabled and a mismatch to the expected value happened. The value is only meaningful, if BERRIF = 1. 0 A low input was sampled, when a high was expected 1 A high input reassembled, when a low was expected
1 BERRIF	Bit Error Interrupt Flag — BERRIF is asserted, when the bit error detect circuitry is enabled and if the value sampled at the RXD input does not match the transmitted value. If the BERRIE interrupt enable bit is set an interrupt will be generated. The BERRIF bit is cleared by writing a "1" to it. 0 No mismatch detected 1 A mismatch has occurred
0 BKDIF	 Break Detect Interrupt Flag — BKDIF is asserted, if the break detect circuitry is enabled and a break signal is received. If the BKDIE interrupt enable bit is set an interrupt will be generated. The BKDIF bit is cleared by writing a "1" to it. 0 No break signal was received 1 A break signal was received



To operate the 16-bit pulse accumulator independently of input capture or output compare 7 and 0 respectively the user must set the corresponding bits IOSx = 1, OMx = 0 and OLx = 0. OC7M7 in the OC7M register must also be cleared.

To enable output action using the OM7 and OL7 bits on the timer port, the corresponding bit OC7M7 in the OC7M register must also be cleared. The settings for these bits can be seen in Table 22-10

	OC71	M7=0		OC7M7=1				
OC7Mx=1		OC7Mx=0		OC7	Mx=1	OC7Mx=0		
TC7=TCx	TC7>TCx	TC7=TCx	TC7>TCx	TC7=TCx	TC7>TCx	TC7=TCx	TC7>TCx	
IOCx=OC7Dx IOC7=OM7/O L7	IOCx=OC7Dx +OMx/OLx IOC7=OM7/O L7	IOCx=0 IOC7=0	Mx/OLx M7/OL7	IOCx=OC7Dx IOC7=OC7D7	IOCx=OC7Dx +OMx/OLx IOC7=OC7D7	IOCx=C IOC7=	0Mx/OLx OC7D7	

Table	22-10.	The	OC7	and	OCx	event	priority
-------	--------	-----	-----	-----	-----	-------	----------

Note: in Table 22-10, the IOS7 and IOSx should be set to 1

IOSx is the register TIOS bit x,

OC7Mx is the register OC7M bit x,

TCx is timer Input Capture/Output Compare register,

IOCx is channel x,

OMx/OLx is the register TCTL1/TCTL2,

OC7Dx is the register OC7D bit x.

IOCx = OC7Dx + OMx/OLx, means that both OC7 event and OCx event will change channel x value.

22.3.2.9 Timer Control Register 3/Timer Control Register 4 (TCTL3 and TCTL4)

Module Base + 0x000A

	7	6	5	4	3	2	1	0
R	EDG7B	EDG7A	EDG6B	EDG6A	EDG5B	EDG5A	EDG4B	EDG4A
W								
Reset	0	0	0	0	0	0	0	0

Figure 22-16. Timer Control Register 3 (TCTL3)

Module Base + 0x000B

_	7	6	5	4	3	2	1	0
R W	EDG3B	EDG3A	EDG2B	EDG2A	EDG1B	EDG1A	EDG0B	EDG0A
Reset	0	0	0	0	0	0	0	0
		Ei a		max Cantral	Deviator / /			

Figure 22-17. Timer Control Register 4 (TCTL4)



FCMD	Command	Function on D-Flash Memory
0x0B	Unsecure Flash	Supports a method of releasing MCU security by erasing all D-Flash (and P-Flash) blocks and verifying that all D-Flash (and P-Flash) blocks are erased.
0x0D	Set User Margin Level	Specifies a user margin read level for the D-Flash block.
0x0E	Set Field Margin Level	Specifies a field margin read level for the D-Flash block (special modes only).
0x0F	Full Partition D- Flash	Erase the D-Flash block and partition an area of the D-Flash block for user access.
0x10	Erase Verify D- Flash Section	Verify that a given number of words starting at the address provided are erased.
0x11	Program D-Flash	Program up to four words in the D-Flash block.
0x12	Erase D-Flash Sector	Erase all bytes in a sector of the D-Flash block.
0x13	Enable EEPROM Emulation	Enable EEPROM emulation where writes to the buffer RAM EEE partition will be copied to the D-Flash EEE partition.
0x14	Disable EEPROM Emulation	Suspend all current erase and program activity related to EEPROM emulation but leave current EEE tags set.
0x15	EEPROM Emulation Query	Returns EEE partition and status variables.
0x20	Partition D-Flash	Partition an area of the D-Flash block for user access.

Table 24-32. D-Flash Commands

24.4.2 Flash Command Description

This section provides details of all available Flash commands launched by a command write sequence. The ACCERR bit in the FSTAT register will be set during the command write sequence if any of the following illegal steps are performed, causing the command not to be processed by the Memory Controller:

- Starting any command write sequence that programs or erases Flash memory before initializing the FCLKDIV register
- Writing an invalid command as part of the command write sequence
- For additional possible errors, refer to the error handling table provided for each command

If a Flash block is read during execution of an algorithm (CCIF = 0) on that same block, the read operation will return invalid data. If the SFDIF or DFDIF flags were not previously set when the invalid read operation occurred, both the SFDIF and DFDIF flags will be set and the FECCR registers will be loaded with the global address used in the invalid read operation with the data and parity fields set to all 0.

If the ACCERR or FPVIOL bits are set in the FSTAT register, the user must clear these bits before starting any command write sequence (see Section 24.3.2.7).

CAUTION

A Flash word or phrase must be in the erased state before being programmed. Cumulative programming of bits within a Flash word or phrase is not allowed.

Register	Error Bit	Error Condition
		Set if CCOBIX[2:0] != 010 at command launch
	ACCERR	Set if command not available in current mode (see Table 24-30)
ESTAT		Set if an invalid DFPART or ERPART selection is supplied ⁽¹⁾
FSTAI	FPVIOL	None
	MGSTAT1	Set if any errors have been encountered during the read
	MGSTAT0	Set if any non-correctable errors have been encountered during the read
FERSTAT	EPVIOLIF	None

Table 24-62. Full Partition D-Flash Command Error Handling
--

1. As defined by the maximum ERPART for FTM256K2.

24.4.2.15 Erase Verify D-Flash Section Command

The Erase Verify D-Flash Section command will verify that a section of code in the D-Flash user partition is erased. The Erase Verify D-Flash Section command defines the starting point of the data to be verified and the number of words.

Table 24-63. Erase Verify D-Flash Section Command FCCOB Requirements

CCOBIX[2:0]	FCCOB Parameters					
000	0x10	Global address [22:16] to identify the D-Flash block				
001	Global address [15:0] of t	he first word to be verified				
010	Number of words to be verified					

Upon clearing CCIF to launch the Erase Verify D-Flash Section command, the Memory Controller will verify the selected section of D-Flash memory is erased. The CCIF flag will set after the Erase Verify D-Flash Section operation has completed.

Global Address (EEEIFRON)	Size (Bytes)	Description
0x12_0000 - 0x12_0001	2	D-Flash User Partition (DFPART) Refer to Section 27.4.2.15, "Full Partition D-Flash Command"
0x12_0002 - 0x12_0003	2	D-Flash User Partition (duplicate ⁽¹⁾)
0x12_0004 - 0x12_0005	2	Buffer RAM EEE Partition (ERPART) Refer to Section 27.4.2.15, "Full Partition D-Flash Command"
0x12_0006 - 0x12_0007	2	Buffer RAM EEE Partition (duplicate ¹)
0x12 0008 0x12 007E	120	Pecarued

Table 27-7. EEE Nonvolatile Information Register Fields

 0x12_0008 - 0x12_007F
 120
 Reserved

 1. Duplicate value used if primary value generates a double bit fault when read during the reset sequence.

27.3.2 **Register Descriptions**

The Flash module contains a set of 20 control and status registers located between Flash module base + 0x0000 and 0x0013. A summary of the Flash module registers is given in Figure 27-4 with detailed descriptions in the following subsections.

CAUTION

Writes to any Flash register must be avoided while a Flash command is active (CCIF=0) to prevent corruption of Flash register contents and Memory Controller behavior.

Address & Name		7	6	5	4	3	2	1	0	
0x0000 FCLKDIV	R W	FDIVLD	FDIV6	FDIV5	FDIV4	FDIV3	FDIV2	FDIV1	FDIV0	
0x0001 FSEC	R W	KEYEN1	KEYEN0	RNV5	RNV4	RNV3	RNV2	SEC1	SEC0	
	ا ر									
0x0002	R	0	0	0	0	0		0000004	0000000	
FCCOBIX	w						CCOBIX2	CCOBIX1	CCOBIX0	
	Þ	0	0	0	0	0				
0x0003		0	0	0	0	0	ECCRIX2	ECCRIX1	ECCRIX0	
FECCHIX	W									
	Ы		0	0		0	0			
0x0004	К	CCIE	0	0	IGNSF	0	0	FDFD	FSFD	
FCNFG	w									
	اح			0						
0x0005	в	ERSERIE	PGMERIE	0	EPVIOLIE	ERSVIE1	EBSVIEO	DFDIE	SEDIE	
FERCNFG	w									

Figure 27-4. FTM512K3 Register Summary



27.4 Functional Description

27.4.1 Flash Command Operations

Flash command operations are used to modify Flash memory contents or configure module resources for EEE operation.

The next sections describe:

- How to write the FCLKDIV register that is used to generate a time base (FCLK) derived from OSCCLK for Flash program and erase command operations
- The command write sequence used to set Flash command parameters and launch execution
- Valid Flash commands available for execution

27.4.1.1 Writing the FCLKDIV Register

Prior to issuing any Flash program or erase command after a reset, the user is required to write the FCLKDIV register to divide OSCCLK down to a target FCLK of 1 MHz. Table 27-9 shows recommended values for the FDIV field based on OSCCLK frequency.

NOTE

Programming or erasing the Flash memory cannot be performed if the bus clock runs at less than 1 MHz. Setting FDIV too high can destroy the Flash memory due to overstress. Setting FDIV too low can result in incomplete programming or erasure of the Flash memory cells.

When the FCLKDIV register is written, the FDIVLD bit is set automatically. If the FDIVLD bit is 0, the FCLKDIV register has not been written since the last reset. If the FCLKDIV register has not been written, any Flash program or erase command loaded during a command write sequence will not execute and the ACCERR bit in the FSTAT register will set.

27.4.1.2 Command Write Sequence

The Memory Controller will launch all valid Flash commands entered using a command write sequence.

Before launching a command, the ACCERR and FPVIOL bits in the FSTAT register must be clear (see Section 27.3.2.7) and the CCIF flag should be tested to determine the status of the current command write sequence. If CCIF is 0, the previous command write sequence is still active, a new command write sequence cannot be started, and all writes to the FCCOB register are ignored.

CAUTION

Writes to any Flash register must be avoided while a Flash command is active (CCIF=0) to prevent corruption of Flash register contents and Memory Controller behavior.

NP

ter 28 768 KByte Flash Module (S12XFTM768K4V2)

Address & Name		7	6	5	4	3	2	1	0
0x0005 FERCNFG	R W	ERSERIE	PGMERIE	0	EPVIOLIE	ERSVIE1	ERSVIE0	DFDIE	SFDIE
0x0006	R	CCIF	0	ACCERR	FPVIOL	MGBUSY	RSVD	MGSTAT1	MGSTAT0
FSTAT	W								
0x0007 FERSTAT	R W	ERSERIF	PGMERIF	0	EPVIOLIF	ERSVIF1	ERSVIF0	DFDIF	SFDIF
0x0008 FPROT	R W	FPOPEN	RNV6	FPHDIS	FPHS1	FPHS0	FPLDIS	FPLS1	FPLS0
0x0009	R	EPOPEN	RNV6	RNV5	RNV4	EPDIS	EPS2	EPS1	EPS0
EPROT	w								
0x000A FCCOBHI	R W	CCOB15	CCOB14	CCOB13	CCOB12	CCOB11	CCOB10	CCOB9	CCOB8
0x000B FCCOBLO	R W	CCOB7	CCOB6	CCOB5	CCOB4	CCOB3	CCOB2	CCOB1	CCOB0
0x000C	R	ETAG15	ETAG14	ETAG13	ETAG12	ETAG11	ETAG10	ETAG9	ETAG8
ETAGHI	w								
0x000D	R	ETAG7	ETAG6	ETAG5	ETAG4	ETAG3	ETAG2	ETAG1	ETAG0
ETAGLO	w								
0x000E	R	ECCR15	ECCR14	ECCR13	ECCR12	ECCR11	ECCR10	ECCR9	ECCR8
FECCRHI	W								
0x000F	R	ECCR7	ECCR6	ECCR5	ECCR4	ECCR3	ECCR2	ECCR1	ECCR0
FECCRLO	w								
0x0010	R	NV7	NV6	NV5	NV4	NV3	NV2	NV1	NV0
FOPT	W								
0x0011	R	0	0	0	0	0	0	0	0
FRSV0	w								
0x0012	R	0	0	0	0	0	0	0	0
FRSV1	W								

Figure 28-4. FTM768K4 Register Summary (continued)



Table 28-16. FERCNFG Field Descriptions (continued)

Field	Description
3 ERSVIE1	 EEE Error Type 1 Interrupt Enable — The ERSVIE1 bit controls interrupt generation when a change state error is detected during an EEE operation. 0 ERSVIF1 interrupt disabled 1 An interrupt will be requested whenever the ERSVIF1 flag is set (see Section 28.3.2.8)
2 ERSVIE0	 EEE Error Type 0 Interrupt Enable — The ERSVIE0 bit controls interrupt generation when a sector format error is detected during an EEE operation. 0 ERSVIF0 interrupt disabled 1 An interrupt will be requested whenever the ERSVIF0 flag is set (see Section 28.3.2.8)
1 DFDIE	 Double Bit Fault Detect Interrupt Enable — The DFDIE bit controls interrupt generation when a double bit fault is detected during a Flash block read operation. 0 DFDIF interrupt disabled 1 An interrupt will be requested whenever the DFDIF flag is set (see Section 28.3.2.8)
0 SFDIE	 Single Bit Fault Detect Interrupt Enable — The SFDIE bit controls interrupt generation when a single bit fault is detected during a Flash block read operation. 0 SFDIF interrupt disabled whenever the SFDIF flag is set (see Section 28.3.2.8) 1 An interrupt will be requested whenever the SFDIF flag is set (see Section 28.3.2.8)

Flash Status Register (FSTAT) 28.3.2.7

The FSTAT register reports the operational status of the Flash module.



Offset Module Base + 0x0006

Figure 28-11. Flash Status Register (FSTAT) 1. Reset value can deviate from the value shown if a double bit fault is detected during the reset sequence (see Section 28.6).

CCIF, ACCERR, and FPVIOL bits are readable and writable, MGBUSY and MGSTAT bits are readable but not writable, while remaining bits read 0 and are not writable.



Table 29-17. FSTAT Field Descriptions

Field	Description
7 CCIF	 Command Complete Interrupt Flag — The CCIF flag indicates that a Flash command has completed. The CCIF flag is cleared by writing a 1 to CCIF to launch a command and CCIF will stay low until command completion or command violation. 0 Flash command in progress 1 Flash command has completed
5 ACCERR	 Flash Access Error Flag — The ACCERR bit indicates an illegal access has occurred to the Flash memory caused by either a violation of the command write sequence (see Section 29.4.1.2) or issuing an illegal Flash command or when errors are encountered while initializing the EEE buffer ram during the reset sequence. While ACCERR is set, the CCIF flag cannot be cleared to launch a command. The ACCERR bit is cleared by writing a 1 to ACCERR. Writing a 0 to the ACCERR bit has no effect on ACCERR. 0 No access error detected 1 Access error detected
4 FPVIOL	Flash Protection Violation Flag — The FPVIOL bit indicates an attempt was made to program or erase an address in a protected area of P-Flash memory during a command write sequence. The FPVIOL bit is cleared by writing a 1 to FPVIOL. Writing a 0 to the FPVIOL bit has no effect on FPVIOL. While FPVIOL is set, it is not possible to launch a command or start a command write sequence. 0 No protection violation detected 1 Protection violation detected
3 MGBUSY	 Memory Controller Busy Flag — The MGBUSY flag reflects the active state of the Memory Controller. 0 Memory Controller is idle 1 Memory Controller is busy executing a Flash command (CCIF = 0) or is handling internal EEE operations
2 RSVD	Reserved Bit — This bit is reserved and always reads 0.
1–0 MGSTAT[1:0]	Memory Controller Command Completion Status Flag — One or more MGSTAT flag bits are set if an error is detected during execution of a Flash command or during the Flash reset sequence. See Section 29.4.2, "Flash Command Description," and Section 29.6, "Initialization" for details.

29.3.2.8 Flash Error Status Register (FERSTAT)

The FERSTAT register reflects the error status of internal Flash operations.



Figure 29-12. Flash Error Status Register (FERSTAT)

All flags in the FERSTAT register are readable and only writable to clear the flag.

Offset Module Base + 0x0007



A.3.1.4 Read Once (FCMD=0x04)

The maximum read once time is given by

$$t = (400) \cdot \frac{1}{f_{\text{NVMBUS}}}$$

A.3.1.5 Load Data Field (FCMD=0x05)

The maximum load data field time is given by

$$t = (450) \cdot \frac{1}{f_{\text{NVMBUS}}}$$

A.3.1.6 Program P-Flash (FCMD=0x06)

The programming time for a single phrase of four P-Flash words + associated eight ECC bits is dependent on the bus frequency as a well as on the frequency f_{NVMOP} and can be calculated according to the following formulas, whereby N_{DLOAD} is the number of extra blocks being programmed by the Load Data Field command (DLOAD), i.e. programming 2,3,4 blocks using DLOAD, N_{DLOAD} =1,2,3 respectively.

The typical phrase programming time can be calculated using the following equation

$$t_{bwpgm} = (128 + (12 \cdot N_{DLOAD})) \cdot \frac{1}{f_{NVMOP}} + (1725 + (510 \cdot N_{DLOAD})) \cdot \frac{1}{f_{NVMBUS}}$$

The maximum phrase programming time can be calculated using the following equation

$$t_{bwpgm} = (130 + (14 \cdot N_{DLOAD})) \cdot \frac{1}{f_{NVMOP}} + (2125 + (510 \cdot N_{DLOAD})) \cdot \frac{1}{f_{NVMBUS}}$$

A.3.1.7 P-Flash Program Once (FCMD=0x07)

The maximum P-Flash Program Once time is given by

 $t_{bwpgm} \approx 162 \cdot \frac{1}{f_{NVMOP}} + 2400 \cdot \frac{1}{f_{NVMBUS}}$

A.3.1.8 Erase All Blocks (FCMD=0x08)

For S12XEP100, S12XEP768, S12XEQ512 and S12XEQ384 erasing all blocks takes:

$$t_{mass} \approx 100100 \cdot \frac{1}{f_{NVMOP}} + 70000 \cdot \frac{1}{f_{NVMBUS}}$$

For S12XET256, S12XEA256 and S12XEG128 erasing all blocks takes:

$$t_{mass} \approx 100100 \cdot \frac{1}{f_{NVMOP}} + 35000 \cdot \frac{1}{f_{NVMBUS}}$$



The standard shipping condition for both the D-Flash and P-Flash memory is erased with security disabled. However it is recommended that each block or sector is erased before factory programming to ensure that the full data retention capability is achieved. Data retention time is measured from the last erase operation.

Condit	Conditions are shown in Table A-4 unless otherwise noted									
Num	С	Rating	Min	Тур	Max	Unit				
P-Flash Arrays										
1	С	Data retention at an average junction temperature of $T_{Javg} = 85^{\circ}C^{(1)}$ after up to 10,000 program/erase cycles	t _{PNVMRET}	15	100 ⁽²⁾	_	Years			
2	С	Data retention at an average junction temperature of $T_{Javg} = 85^{\circ}C^{(3)}$ after less than 100 program/erase cycles	t _{PNVMRET}	20	100 ²	_	Years			
3	С	P-Flash number of program/erase cycles $(-40^{\circ}C \le tj \le 150^{\circ}C)$	n _{PFLPE}	10K	100K ³	_	Cycles			
		D-Flash Array								
4	С	Data retention at an average junction temperature of $T_{Javg} = 85^{\circ}C^{3}$ after up to 50,000 program/erase cycles	t _{DNVMRET}	5	100 ²	_	Years			
5	С	Data retention at an average junction temperature of $T_{Javg} = 85^{\circ}C^{3}$ after less than 10,000 program/erase cycles	t _{DNVMRET}	10	100 ²	_	Years			
6	С	Data retention at an average junction temperature of $T_{Javg} = 85^{\circ}C^{3}$ after less than 100 program/erase cycles	t _{DNVMRET}	20	100 ²	_	Years			
7	С	D-Flash number of program/erase cycles (-40°C \leq tj \leq 150°C)	n _{DFLPE}	50K	500K ³		Cycles			
	_	Emulated EEPROM								
8	С	Data retention at an average junction temperature of $T_{Javg} = 85^{\circ}C^{1}$ after spec. program/erase cycles	t _{EENVMRET}	5 ⁴	100 ²	_	Years			
9	С	Data retention at an average junction temperature of T _{Javg} = 85°C ³ after less than 20% spec.program/erase cycles. (e.g. after <20,000 cycles / Spec 100,000 cycles)	t _{EENVMRET}	10	100 ²	_	Years			
10	С	Data retention at an average junction temperature of $T_{Javg} = 85^{\circ}C^{3}$ after less than 0.2% spec. program/erase cycles (e.g. after < 200 cycles / Spec 100,000 cycles)	t _{EENVMRET}	20	100 ²	_	Years			
11	С	EEPROM number of program/erase cycles with a ratio of EEE_NVM to EEE_RAM = 8 (-40°C \leq tj \leq 150°C)	n _{EEPE}	100K ⁽⁴⁾	1M ⁽⁵⁾	_	Cycles			
12	С	EEPROM number of program/erase cycles with a ratio of EEE_NVM to EEE_RAM = 128 (-40°C \leq tj \leq 150°C)	n _{EEPE}	3M ⁴	30M ⁵		Cycles			
13	С	EEPROM number of program/erase cycles with a ratio of EEE_NVM to EEE_RAM = $16384^{(6)}$ (- $40^{\circ}C \le tj \le 150^{\circ}C$)	n _{EEPE}	325M ⁴	3.2G ⁵	_	Cycles			

Table A-20. NVM Reliability Characteristics

1. T_{Javg} does not exceed 85°C in a typical temperature profile over the lifetime of a consumer, industrial or automotive application.

 Typical data retention values are based on intrinsic capability of the technology measured at high temperature and de-rated to 25°C using the Arrhenius equation. For additional information on how Freescale defines Typical Data Retention, please refer to Engineering Bulletin EB618

3. T_{Javg} does not exceed 85°C in a typical temperature profile over the lifetime of a consumer, industrial or automotive application.

 This represents the number of writes of updated data words to the EEE_RAM partition. Minimum specification (endurance and data retention) of the Emulated EEPROM array is based on the minimum specification of the D-Flash array per item 6.



In Table A-29 the timing characteristics for slave mode are listed.

Num	С	Characteristic	Symbol	Min	Тур	Мах	Unit
1	D	SCK frequency	f _{sck}	DC	_	1/4	f _{bus}
1	D	SCK period	t _{sck}	4	—	∞	t _{bus}
2	D	Enable lead time	t _{lead}	4	_	—	t _{bus}
3	D	Enable lag time	t _{lag}	4	_	—	t _{bus}
4	D	Clock (SCK) high or low time	t _{wsck}	4	—	_	t _{bus}
5	D	Data setup time (inputs)	t _{su}	8	_	—	ns
6	D	Data hold time (inputs)	t _{hi}	8	_	_	ns
7	D	Slave access time (time to data active)	t _a	_	—	20	ns
8	D	Slave MISO disable time	t _{dis}	_	_	22	ns
9	D	Data valid after SCK edge	t _{vsck}	—	—	$28 + 0.5 \cdot t_{bus}^{(1)}$	ns
10	D	Data valid after SS fall	t _{vss}		—	$28 + 0.5 \cdot t_{bus}^{1}$	ns
11	D	Data hold time (outputs)	t _{ho}	20	_	—	ns
12	D	Rise and fall time inputs	t _{rfi}		—	8	ns
13	D	Rise and fall time outputs	t _{rfo}		—	8	ns

Table A-29. SPI Slave Mode Timing Characteristics

1. 0.5 t_{bus} added due to internal synchronization delay